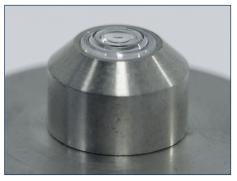




LUPHOScan⁵⁰ SL







The world's fastest and most accurate system, for non-contact 3D cellphone lens metrology.

LUPHOScan SL

Ultra fast, non-contact, 3D form measurement

Measure cellphone lenses in <60 seconds

Based on the industry standard LUPHOScan platform

Introducing, the LUPHOScan SL with new probe technology for increased measurement flexibility and ultra fast measurement times down to < 60 seconds.

The LUPHOScan SL is ideal for high volume production of small lenses with key benefits of the system including ultra fast measurement speeds and the ability to measure geometric lens features.

Unique benefits for both design and production.

- Ultra high, repeatable accuracy
 ≤ 30 nm PV (3σ)
- Best available stability
 Power variation < ± 15 nm (3σ),
 PV variation < ± 1.5 nm (3σ)
- Analyse geometric features
 Such as interlocks and edge diameters in relation to each other or the optical surface
- Thin transparent substrates

 Down to 100 µm thickness
- Fast measurement speeds for true 3D
 < 120 sec. Optical surface and geometric features*
 - < 60 sec. Optical surface only**

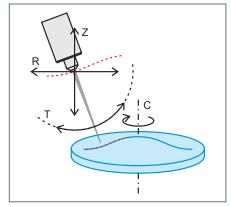


Measurement principle

During measurement the probe performs a spiral scan over the entire surface of the object under test and produces high density 3D data.

Scanning is achieved by rotating the object by means of an air-bearing spindle whilst the sensor is moved radially and axially using linear stages.

A rotary stage keeps the sensor normal to the object surface. The layout of movement stages provides high flexibility, even for uncommon surface shapes including steep slopes or profiles with points of inflection.



Movement of the LUPHOScan object sensor

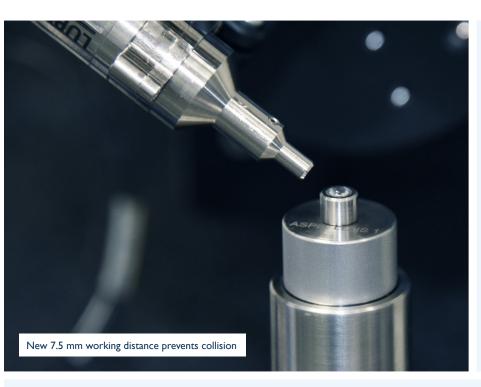
^{*} Such as surface flats, interlocks and edge diameters.

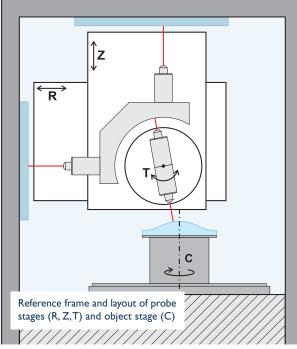
^{**} Geometry and lateral resolution dependant.

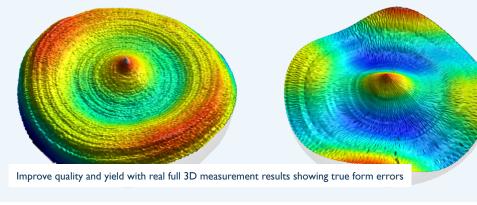
Advanced capability delivers world's fastest measurement of 3D surface and interlocks

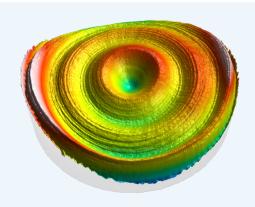
< 120 sec. cycle time

99







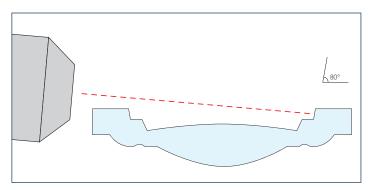


Optimised LUPHOScan probe.

The new probe technology used on the LUPHOScan SL adds additional benefits including an increased working distance of 7.5 mm.

This enables complex geometric features on lens moulds and moulded lenses to be measured, such as:

- Access to measure interlocks without collision between the probe and substrate.
- Increased access to steep concave optical surfaces

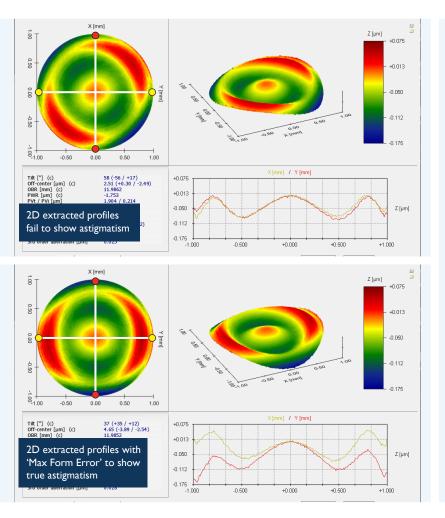


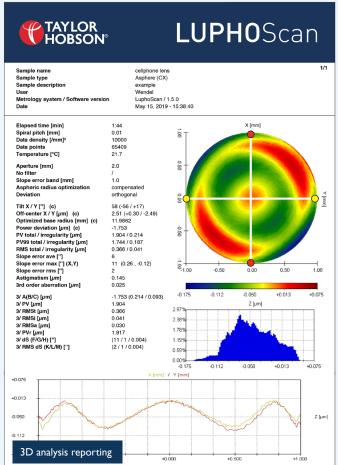
Improve measurements of interlocks without collision

Lens form metrology

Increased yield and quality with true 3D accuracy

3D measurement & analysis in < 60 seconds





Fully automated analysis options for professional reporting.

2D extracted profiles with 'Max Form Error' feature.

Form error results can be automatically optimised to output the maximum form error present on a part.

Only true 3D measurements can provide this level of form error information.

The example shown identifies that the same 3D form error can yield two completely different 2D form errors.

3D measurement with 3D surfaces for in-depth reporting.

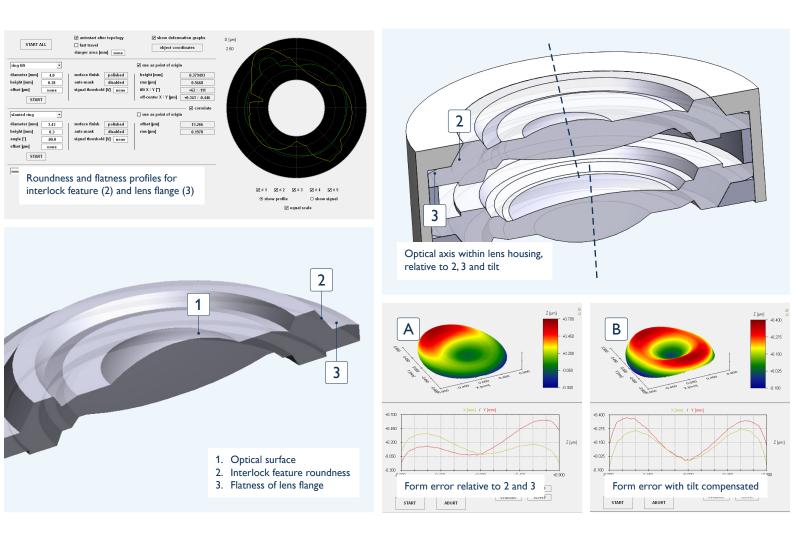
Measurement results can be output showing the complete surface form error with the 3D option, including extracted 2D profiles.

- ISO compliant analysis results (ISO 10110).
- · Auto export results for quality control and traceability.
- Export 3D measured surface in common formats for process improvement.
- Set pass/fail criteria for easy process control.

Advanced lens metrology

Increased productivity with world's fastest measurement

3D optical surface & interlocks in < 120 seconds



Fast measurement and analysis of the optical surface and geometrical features.

Measure the optical surface and geometrical features such as interlock surface roundness, flatness of the flat lens surface and location of the optical surface relative to these features.

Optical surface is off centre and tilted relative to the interlock feature position and lens flange.

The analysed results (A) show the lens form error of the optical surface relative to the interlock and lens flange.

The results highlight the real form error which would be seen if the lens had been put into an assembly and aligned relative to these features.

The optical surface (B) shows the tilt compensated form error.



Typical cellphone lens assembly

Tooling system

Simple tooling system for increased throughput

Rapid set-up with no alignment required

Save time with easy part set-up and measurement.

The easy-to-use tooling enables accurate measurements with simple set-up.

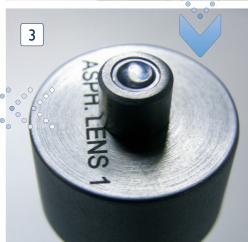
- 1. LUPHOScan SL system with tooling chuck
- 2. Dedicated lens mount.
- 3. Lens loaded into lens mount.
- 4. Lens measurement using LUPHOScan SL, lens mount and tooling chuck.



Tray of multiple lens holders, enabling fast changing







Critical results, trust Taylor Hobson.

Easy, fast & accurate calibration.

- High quality calibration with 3 artefacts (included as standard).
- Calibration artefact compatible with tooling chuck
- Easy-to-use interface with no alignment required.
- Complete calibration cycle takes only 15 minutes





Specification

Industry leading accuracy for the competitive edge

LUPHOScan⁵⁰ SL HD

Measurement characteristics ¹		HD System			
Form measurement accuracy ² (3 σ)		30 nm (30°)	30°) 70 nm (70°)		100 nm (90°)
Measurement repeatability	Power (PWR)	30 nm (30°)	60 nm	(70°)	90 nm (90°)
	Peak-to-Valley (PV99)	3 nm (30°)	8 nm	(70°)	10 nm (90°)
Spotsize of point probe		6 µm			
Lateral resolution (points per mm²)		(adjustable) up to 2×10 ^s			
Measurement time (Full 3D)		Optical surface & two geometric features - < 120 sec.		Optical surface only - < 60 sec.	

Measurement system				
Machine type	4-axis (3 roller bearings, 1 air bearing)			
Measurement principle	Scanning point interferometry			
Sensor technology	Fibre optics based multi-wavelength interferometer (MWLI®)			
Scanning mode (3D)	Spiral, equidistant, normal			
Measurement volume (D \times H)	50 × 75 mm			
Maximum tilt	90°			
	3 MWLI® sensors			
Reference system	Invar frame			
Neid chee System	Compensation of 1st order errors by R, Z,T axes (Abbe principle)			

Data handling			
Parameter input		Aspheric coefficients (even, odd), AAU (.dcof /.design), DiffSys freeform (.pgm), BaSys (.asp), HMF (.hmf)	
Measurement data		3D	
Data export formats	3D	MetroPro (.xyz/.dat),TalyMap (.sur), X,Y,Z,dP (.ascii, binary), Satisloh (.hmf), Zeiss (.wve), OpticStudio (.dat)	
	2D	Taylor Hobson (.mod, .prf), X, Z, dP (.ascii, binary)	
Export methods		Manual and automatic (user definable)	
Data analysis		3D surface visualisation, adjustable cross section, 2D graphics, 2D Max form erro filtering (LPF, HPF, mean value filter), best-fit radius, aspheric fit, Power, PV, RM Slope errors, Zernike, ISO 10110	
Measurement report		PDF (user definable)	

Object parameters				
Surface shapes		Aspheric, spheric, flat, slight freeform and most other optical surface geometries		
Surface finish		Polished, rough, transparent, specular, opaque		
Minimum substrate thickness ³		100 μm		
Reflectivity range		0.1 % 100 %		
Spherical departure ⁴		Unrestricted		
Maximal slopes	Convex	90°		
Maximai siopes	Concave ⁵	-85°		
Maximal diameter (90° slope)		50 mm		
Diameter of largest measurable hemisphere		50 mm		
Maximal SAG heights	Convex	55 mm		
	Concave	25 mm		
Maximum object diameter		50 mm		
Maximum object weight		12 kg		

Machine characteristics			
Object mount	Hydraulic expansion chuck (HD25), optional: 3-jaw chuck, centre & levelling table, optimised lens tooling		
Internal data rate	2500 Hz		
Wavelength range	1530 nm 1610 nm		
Laser classification	Class 1		
Laser Classification	Continuous wave output (CW), < 1 mW		
Machine dimensions (W \times D \times H)	$73 \times 81 \times 190 \text{ cm}$		
Machine weight	325 kg		
Compressed air requirement	8 10 bar, 20 litre/min		
Electrical power requirement	230 VAC, 50/60 Hz, < 700 W		

Qualifiers

- For polished surfaces, depending on environmental conditions.
- 2. PV for measurements on spherical reference standard.
- Transparent substrate.
- 4. Object sensor follows ideal profile.
- Part diameter < 6 mm.

Taylor Hobson pursues a policy of continual improvements due to technical developments. We therefore reserve the right to deviate from catalogue specifications.





The Metrology Experts

Established in 1886, Taylor Hobson is the world leader in surface and form metrology and developed the first roundness and surface finish measuring instruments.

www.taylor-hobson.com

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- Design engineering special purpose, dedicated metrology systems for demanding applications.
- Precision manufacturing contract machining services for high precision applications and industries.

Centre of Excellence department

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- Operator training on-site instruction will lead to greater proficiency and higher productivity.
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• Preventative maintenance - protect your metrology investment with an AMECare support agreement.







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